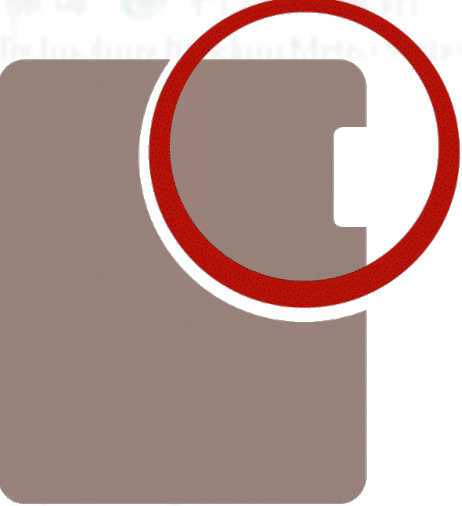
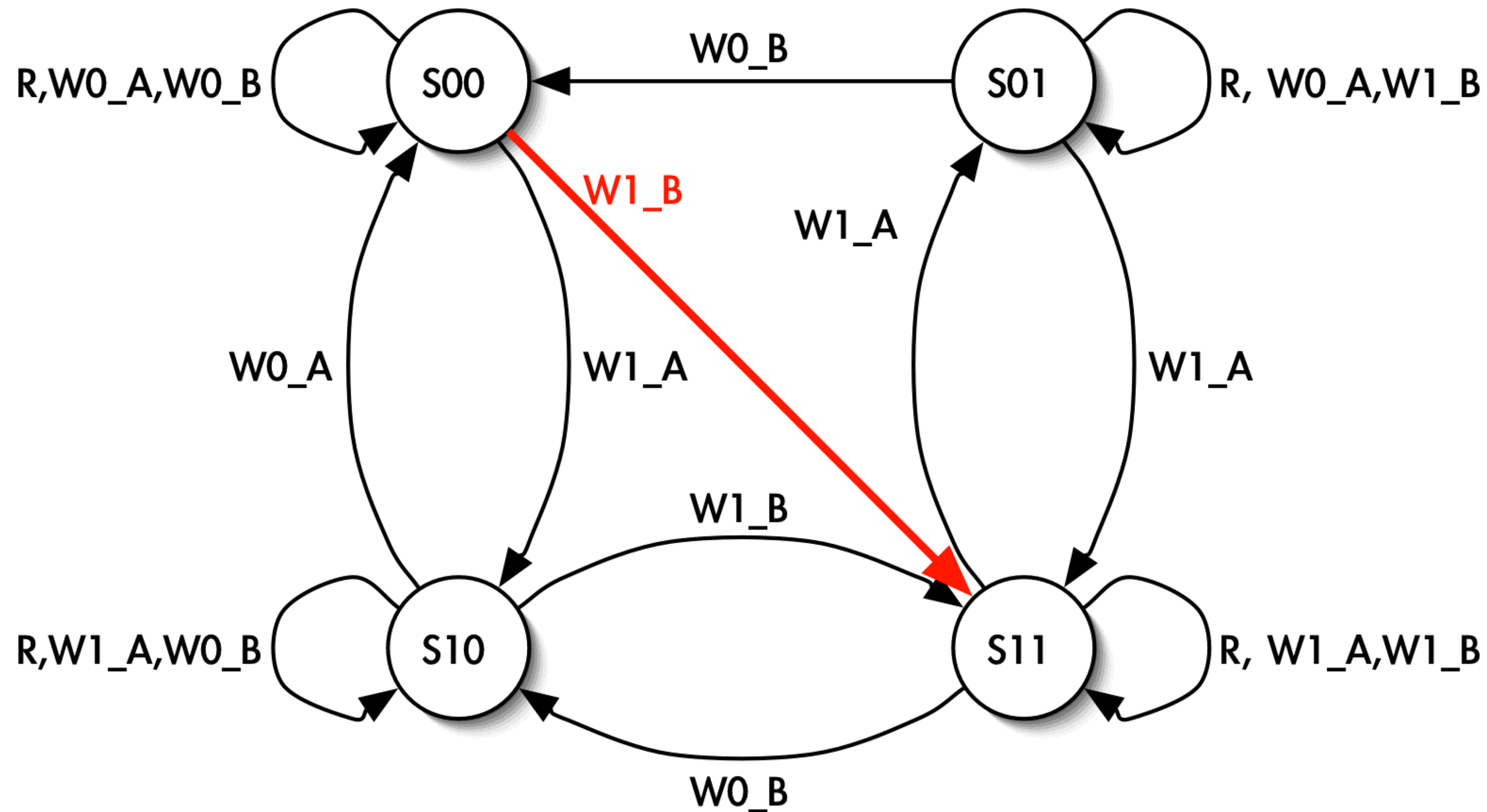
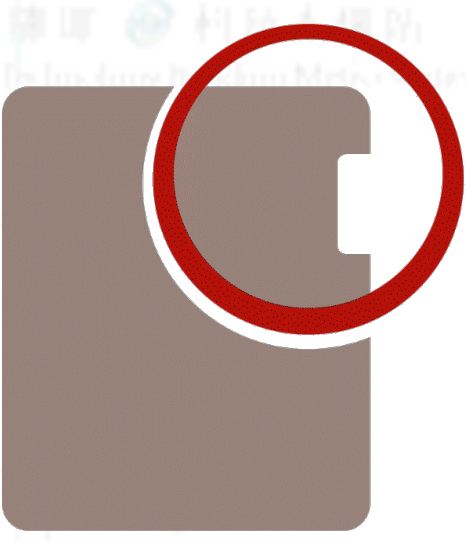


HW 03-1 Coupling Fault



Let A and B be two adjacent memory cells. Find one test pattern (that we discussed in the classroom) that detects the following coupling fault. Show how your pattern detects the fault.

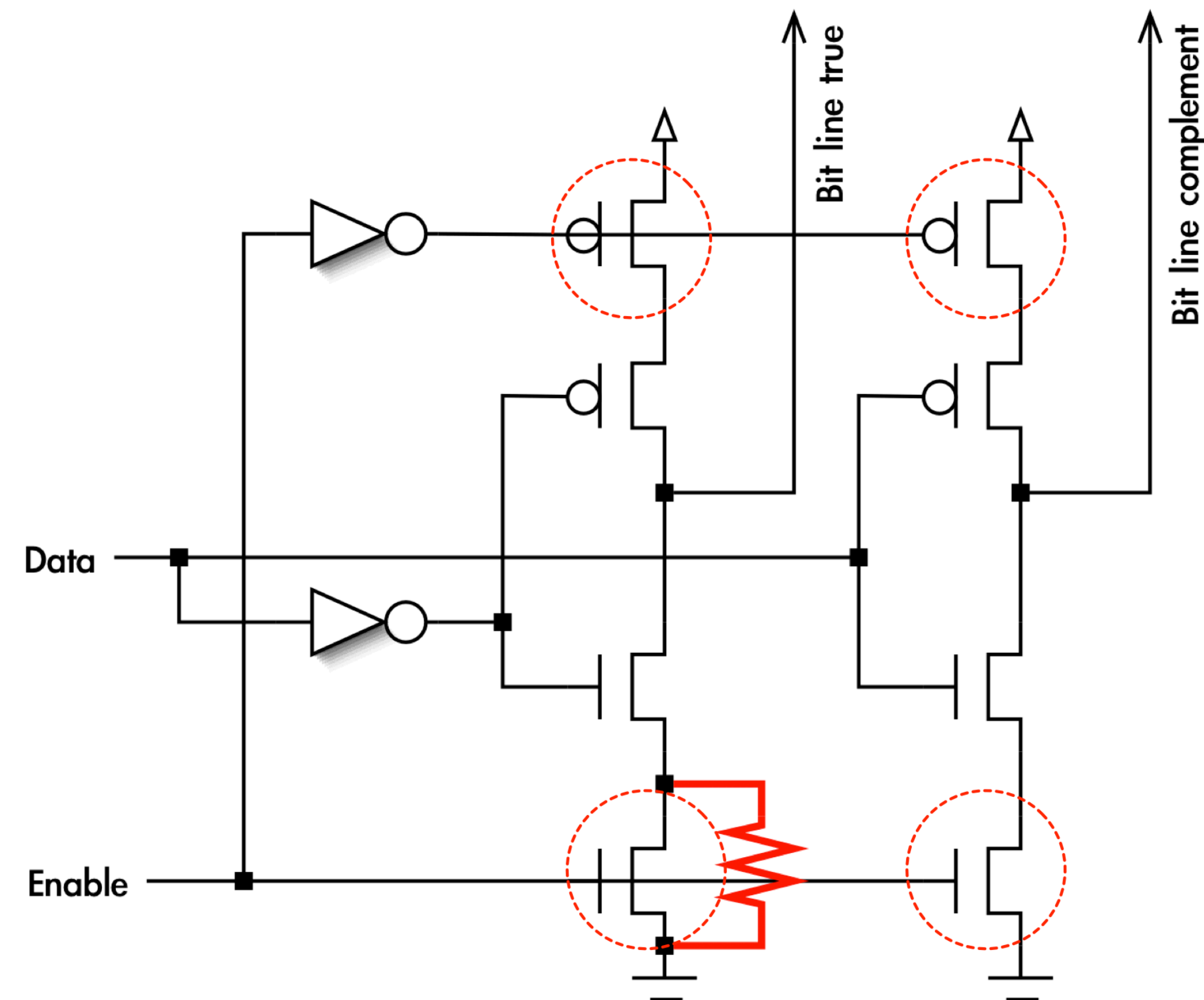




- First, set AB to 00.
- Then, apply r0w1.
 - If $A < B$, detected w/ decreasing address order.
 - If $A > B$, detected w/ increasing address order.
 - Detection:
 - fault-free: $00 \Rightarrow 01 \Rightarrow 11$
 - faulty: $00 \Rightarrow \underline{11}$
 - Example: March C- $\left\{ \Updownarrow (w0); \underline{\Uparrow (r0,w1)}; \Uparrow (r1,w0); \underline{\Downarrow (r0,w1)}; \Downarrow (r1,w0); \Updownarrow (r0) \right\}$

HW 03-2 False Write Through

- Advise a test pattern that detects the short faults at the four circled transistors. Show how the faults are detected.





Assume that “Data” stays at its last value unless a new write operation is performed.

1. The true bit line PMOS stuck-on (site A) will prevent the true bit line from being pulled down. Thus, it can be detected by the r0 operation following a w1 operation (to set Data to 1) *at the same column* that sets “Data” to 1, e.g., (r0 ... w1). Note that the address order should be *row first*.
2. The complement bit line NMOS stuck-on (site D) will prevent the complement bit line from being pulled up, which is similar to a recharge fault. This can be activated by w1 followed by r0 (at the same column) — the voltage at the complement bit line may be lower than that in the true bit line due to the imperfect pre-charge. The detecting element is (r0 ... w1).
3. The complement bit line PMOS stuck-on (site B) will prevent the complement bit line from being pulled down. To activate it, we must set Data to 0 (by w0). An r1 may fail because the complement bit line may not be sufficiently low (compared to the true bit line). The detecting element is {r1 ... w0} — row first.
4. The analysis is similar to case 2. The detecting element is (r1 ... w0).

Many memory test patterns have the elements to detect these faults, for example, March C-.

$$\{ \updownarrow (w0); \uparrow (r0,w1); \uparrow (r1,w0); \downarrow (r0,w1); \downarrow (r1,w0); \updownarrow (r0) \}$$

Note that the address order has to be *row-first*.

